FCC ID: 2AFHP-EP-B60

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V05

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances \leq 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] * [$\sqrt{f(GHz)}$] ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where

f(GHz) is the RF channel transmit frequency in GHz;

Power and distance are rounded to the nearest mW and mm before calculation;

The result is rounded to one decimal place for comparison;

The test exclusions are applicable only when the minimum test separation distance is \leq 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion. We use 5mm as separation distance to calculated.

Bluetooth DSS:

Transmit Frequency	Mode	Measured Power	Tune-up power	Max tune-up	Result	1g SAR
(GHz)		(dBm)	(dBm)	power(dBm)	calculation	
2.402	GFSK	-0.742	-1±1	0	0.3100	3
2.441		-1.754	-1±1	0	0.3125	3
2.48		-0.555	-1±1	0	0.3150	3
2.402	π/4-DQPSK	-3.201	-3±1	-2	0.1956	3
2.441		-2.046	-3±1	-2	0.1972	3
2.48		-2.784	-3±1	-2	0.1987	3
2.402	8DPSK	-2.577	-2±1	-1	0.2462	3
2.441		-1.284	-2±1	-1	0.2482	3
2.48		-2.401	-2±1	-1	0.2502	3

Bluetooth DTS:

Transmit Frequency (GHz)	Mode	Measured Power (dBm)	Tune-up power (dBm)	Max tune-up	Result	1g SAR
				power(dBm)	calculation	
2.402	GFSK	1.066	1±1	2	0.4913	3
2.44		1.736	1±1	2	0.4951	3
2.48		0.855	1±1	2	0.4992	3

Conclusion:

For the max result : 0.4992≤ 3.0 for 1g SAR, No SAR is required.

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Signature:

Date: 2017-10-21

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